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is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to This collection of information is required by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete including gathering, preparing, and process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete including gathering, preparing, and process) an application form to the USPTO. Time will vary depending upon the includdual case. Any comments on the amount of time you require to complete this submitting the completed application form to the USPTO. Time will vary depending upon the includdual case. Any comments on the amount of time you require to complete this submitting the complete application form to the USPTO. Time will vary depending upon the included as a not case. Any comments on the amount of time you require to complete this submitting the Comments of the process of the process

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